# PH9030L

# N-channel TrenchMOS logic level FET Rev. 01 — 29 July 2008

**Product data sheet** 

# 1. Product profile

#### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

#### 1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

#### 1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Portable equipment
- Switched-mode power supplies

#### 1.4 Quick reference data

Table 1. **Quick reference** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Symbol	raiailletel	Conditions	IAIIII	ıуp	IVIAX	Uill
$V_{DS}$	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	-	30	V
I <sub>D</sub>	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	63	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \underline{\text{Figure 10}};$ $\text{see } \underline{\text{Figure 11}}$	-	3.2	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 8}}{\text{Figure 9}}; \text{ see } \frac{\text{Figure 8}}{\text{Figure 9}}$	-	7	9	mΩ



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# 2. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1,2,3	S	source		5
4	G	gate	mb (	D
	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH9030L	LFPAK	Plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	30	V
$V_{DGR}$	drain-gate voltage	25 °C $\leq$ T <sub>j</sub> $\leq$ 150 °C; R <sub>GS</sub> = 20 k $\Omega$	-	30	V
V <sub>GS</sub>	gate-source voltage		-20	20	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_j = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{}$	-	39	Α
		$V_{GS} = 10 \text{ V}$ ; $T_{mb} = 25 \text{ °C}$ ; see Figure 1; see Figure 3	-	63	Α
I <sub>DM</sub>	peak drain current	$t_p \le 10 \mu s$ ; pulsed; $T_{mb} = 25  ^{\circ}C$ ; see Figure 3	-	214	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	in diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	52	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	208	Α
Avalanche	Ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 33 A; $V_{sup}$ ≤ 30 V; unclamped; $t_p$ = 0.08 ms; $R_{GS}$ = 50 Ω	-	53	mJ

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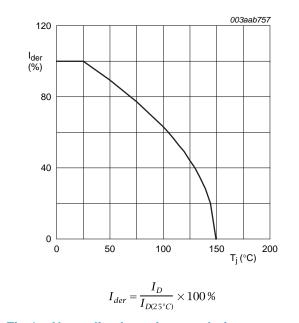


Fig 1. Normalized continuous drain current as a function of solder point temperature

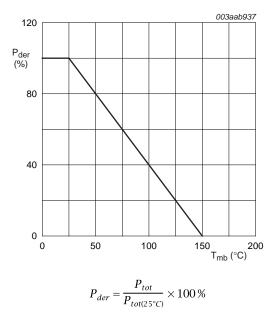
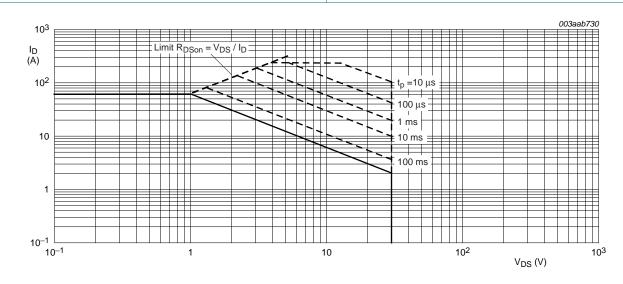


Fig 2. Normalized total power dissipation as a function of solder point temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$  is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W

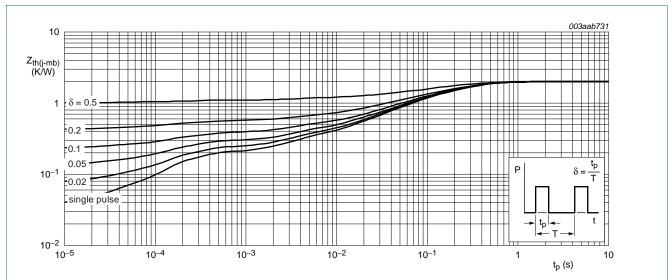


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration

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## 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS} \\$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 ^{\circ}C$	30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 25 ^{\circ}\text{C}$ ; see Figure 6; see Figure 7	1.3	1.7	2	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = -55 \text{ °C}$ ; see Figure 7; see Figure 6	-	-	2.6	V
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 150 \text{ °C}$ ; see <u>Figure 7</u> ; see <u>Figure 6</u>	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 150 ^{\circ}\text{C}; \text{ see}$ Figure 8; see Figure 9	-	11.9	15.8	mΩ
		$V_{GS} = 4.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; $T_j = 25 \text{ °C}$ ; see Figure 8; see Figure 9	-	10	12.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}; \text{ see}$ Figure 8; see Figure 9	-	7	9	mΩ
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	100	μΑ
$R_{G}$	internal gate resistance (AC)	f = 1 MHz	-	0.56	-	Ω
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ; see	-	13.3	-	nC
$Q_GS$	gate-source charge	Figure 10; see Figure 11	-	4.8	-	nC
$Q_{GD}$	gate-drain charge		-	3.2	-	nC
$Q_{\text{GS(th)}}$	pre-threshold gate-source charge		-	1.8	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	3	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	2.72	-	V
C <sub>iss</sub>	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{ V}}$	-	1565	-	pF
		$V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$	-	1839	-	pF
C <sub>oss</sub>	output capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	355	-	pF
C <sub>rss</sub>	reverse transfer capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 12</u>	-	186	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 12 V; $R_L$ = 0.5 $\Omega$ ; $V_{GS}$ = 4.5 V;	-	20	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5.6 \Omega$	-	41	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	15	-	ns

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Table 6. Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t <sub>f</sub>	fall time	$\begin{split} V_{DS} &= 12 \text{ V}; \text{ R}_{L} = 0.5 \Omega; \text{ R}_{L} = 0.5 \Omega; \\ V_{GS} &= 4.5 \text{ V}; \text{ R}_{G(ext)} = 5.6 \Omega \end{split}$	-	25	-	ns
Source-drain	n diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 14	-	0.89	1.16	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	43	-	ns
Q <sub>r</sub>	recovered charge	$V_{DS} = 30 \text{ V}$	-	15	-	nC

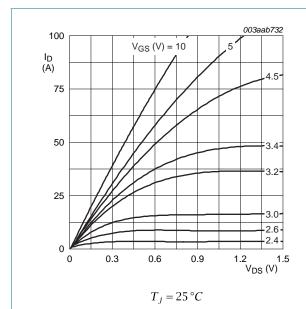


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

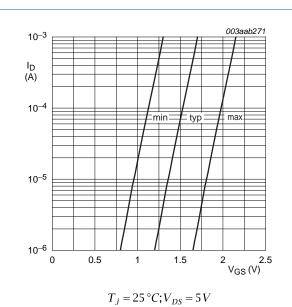


Fig 6. Sub-threshold drain current as a function of gate-source voltage

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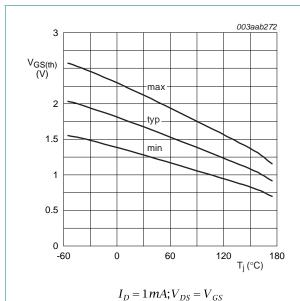


Fig 7. Gate-source threshold voltage as a function of junction temperature

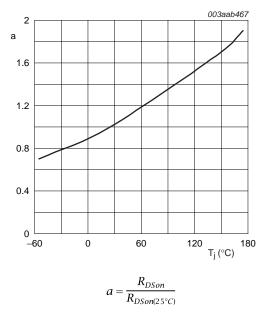


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature

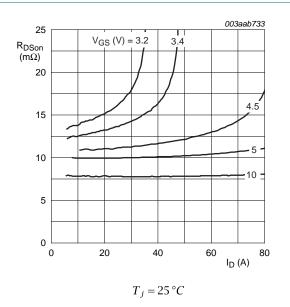


Fig 8. Drain-source on-state resistance as a function of drain current; typical values

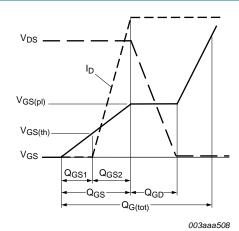
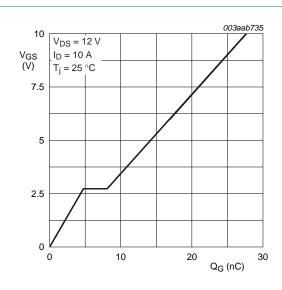


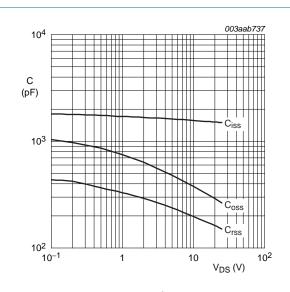
Fig 10. Gate charge waveform definitions

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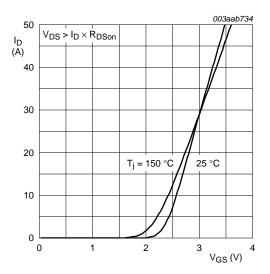
 $I_D = 10A; V_{DS} = 12V$ 

Fig 11. Gate-source voltage as a function of gate charge; typical values



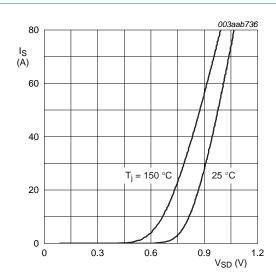
$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $T_j = 25 \,^{\circ}C$  and  $150 \,^{\circ}C$ ;  $V_{DS} > I_D \times R_{DSon}$ 

Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25 \,^{\circ}C$  and  $150 \,^{\circ}C$ ;  $V_{GS} = 0 \, V$ 

Fig 14. Source current as a function of source-drain voltage; typical values

## 7. Package outline

#### Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

04-10-13

06-03-16

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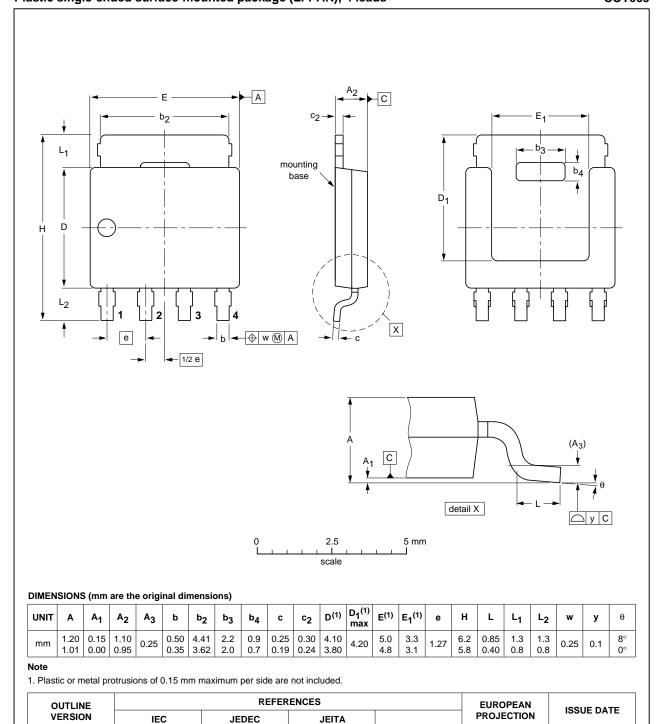


Fig 15. Package outline SOT669 (LFPAK)

SOT669

MO-235

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# **Revision history**

#### Table 7. **Revision history**

**Product data sheet** 

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH9030L_1	20080729	Product data sheet	-	-

#### N-channel TrenchMOS logic level FET

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#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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- [2] The term 'short data sheet' is explained in section "Definitions".
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